


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

 [Search Results](#)
[BROWSE](#)[SEARCH](#)[IEEE Xplore GUIDE](#)

Results for "(((alumina <and> magnetic <and> gap)<in>metadata)) <and> (pyr >= 1951 <...>"

[e-mail](#)

Your search matched 5 of 1472243 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by **Relevance** in **Descending** order.» [Search Options](#)[View Session History](#)[New Search](#)[Modify Search](#)

[Search](#)
 Check to search only within this results set
» [Key](#)Display Format: Citation Citation & Abstract

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

 [Select All](#) [Deselect All](#)

1. **A study of the microcracks on the alumina of the thin-film head**
 Chekanov, A.S.; Low, T.S.; Alli, S.;
Physical and Failure Analysis of Integrated Circuits, 1995., Proceedings of the International Symposium on the
27 Nov.-1 Dec. 1995 Page(s):176 - 180
Digital Object Identifier 10.1109/IPFA.1995.487619
[AbstractPlus](#) | Full Text: [PDF\(416 KB\)](#) IEEE CNF
[Rights and Permissions](#)
2. **Microcracks of the thin-film head alumina: "L" cracks and "U" cracks**
 Chekanov, A.S.; Low, T.S.; Alli, S.; Kolosov, O.; Briggs, A.;
Magnetics, IEEE Transactions on
Volume 32, Issue 5, Part 1, Sept. 1996 Page(s):3696 - 3698
Digital Object Identifier 10.1109/20.538807
[AbstractPlus](#) | Full Text: [PDF\(548 KB\)](#) IEEE JNL
[Rights and Permissions](#)
3. **ETA-II accelerator upgrades**
 Nilson, D.G.; Deadrick, F.J.; Hibbs, S.M.; Petersen, D.E.; Sampayan, S.E.;
Fusion Engineering, 1991. Proceedings., 14th IEEE/NPSS Symposium on
30 Sept.-3 Oct. 1991 Page(s):1179 - 1182 vol.2
Digital Object Identifier 10.1109/FUSION.1991.218661
[AbstractPlus](#) | Full Text: [PDF\(348 KB\)](#) IEEE CNF
[Rights and Permissions](#)
4. **MR sensor oxidation mechanism at high temperature**
 Chang Xie; Davis, M.; Schultz, A.;
Magnetics, IEEE Transactions on
Volume 35, Issue 5, Part 1, Sept. 1999 Page(s):2619 - 2621
Digital Object Identifier 10.1109/20.800914
[AbstractPlus](#) | Full Text: [PDF\(384 KB\)](#) IEEE JNL
[Rights and Permissions](#)
5. **Suppression of leakage and crosstalk in typical millimeter-wave flip-chip**
 Gue-An Lee; Hai-Young Lee;
Electrical Performance of Electronic Packaging, 1997., IEEE 6th Topical Meeti
27-29 Oct. 1997 Page(s):195 - 198
Digital Object Identifier 10.1109/EPEP.1997.634069